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"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	50MHz
Connectivity	I ² C, IrDA, SPI, UART/USART
Peripherals	DMA, I ² S, LVD, POR, PWM, WDT
Number of I/O	64
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	4K x 8
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 3.6V
Data Converters	A/D 24x16b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	121-LFBGA
Supplier Device Package	121-MAPBGA (8x8)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mk11dx128avmc5

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong





1 Ordering parts

1.1 Determining valid orderable parts

Valid orderable part numbers are provided on the web. To determine the orderable part numbers for this device, go to freescale.com and perform a part number search for the following device numbers: PK11 and MK11.

2 Part identification

2.1 Description

Part numbers for the chip have fields that identify the specific part. You can use the values of these fields to determine the specific part you have received.

2.2 Format

Part numbers for this device have the following format:

Q K## A M FFF R T PP CC N

2.3 Fields

This table lists the possible values for each field in the part number (not all combinations are valid):

Field	Description	Values
Q	Qualification status	 M = Fully qualified, general market flow P = Prequalification
K##	Kinetis family	• K11
A	Key attribute	 D = Cortex-M4 w/ DSP F = Cortex-M4 w/ DSP and FPU
М	Flash memory type	 N = Program flash only X = Program flash and FlexMemory

Table continues on the next page...



ran identification

Field	Description	Values
FFF	Program flash memory size	 32 = 32 KB 64 = 64 KB 128 = 128 KB 256 = 256 KB 512 = 512 KB 1M0 = 1 MB 2M0 = 2 MB
R	Silicon revision	 Z = Initial (Blank) = Main A = Revision after main
Т	Temperature range (°C)	 V = -40 to 105 C = -40 to 85
PP	Package identifier	 FM = 32 QFN (5 mm x 5 mm) FT = 48 QFN (7 mm x 7 mm) LF = 48 LQFP (7 mm x 7 mm) LH = 64 LQFP (10 mm x 10 mm) MP = 64 MAPBGA (5 mm x 5 mm) LK = 80 LQFP (12 mm x 12 mm) LL = 100 LQFP (14 mm x 14 mm) MC = 121 MAPBGA (8 mm x 8 mm) LQ = 144 LQFP (20 mm x 20 mm) MD = 144 MAPBGA (13 mm x 13 mm)
СС	Maximum CPU frequency (MHz)	 5 = 50 MHz 7 = 72 MHz 10 = 100 MHz 12 = 120 MHz 15 = 150 MHz 18 = 180 MHz
N	Packaging type	 R = Tape and reel (Blank) = Trays

2.4 Example

This is an example part number:

MK11DN512VMC5

2.5 Small package marking

In an effort to save space, small package devices use special marking on the chip. These markings have the following format:

Q ## C F T PP

This table lists the possible values for each field in the part number for small packages (not all combinations are valid):



Terminology and guidelines

Field	Description	Values
Q	Qualification status	 M = Fully qualified, general market flow P = Prequalification
С	Speed	• G = 50 MHz
F	Flash memory configuration	 G = 128 KB + Flex H = 256 KB + Flex 9 = 512 KB
Т	Temperature range (°C)	• V = -40 to 105
PP	Package identifier	• MC = 121 MAPBGA

This tables lists some examples of small package marking along with the original part numbers:

Original part number	Alternate part number		
MK11DX128VLK5	M11GGVLK		
MK11DX256VMC5	M11GHVMC		

3 Terminology and guidelines

3.1 Definition: Operating requirement

An *operating requirement* is a specified value or range of values for a technical characteristic that you must guarantee during operation to avoid incorrect operation and possibly decreasing the useful life of the chip.

3.1.1 Example

This is an example of an operating requirement:

Symbol	Description	Min.	Max.	Unit
V _{DD}	1.0 V core supply voltage	0.9	1.1	V



3.7 Guidelines for ratings and operating requirements

Follow these guidelines for ratings and operating requirements:

- Never exceed any of the chip's ratings.
- During normal operation, don't exceed any of the chip's operating requirements.
- If you must exceed an operating requirement at times other than during normal operation (for example, during power sequencing), limit the duration as much as possible.

3.8 Definition: Typical value

A *typical value* is a specified value for a technical characteristic that:

- Lies within the range of values specified by the operating behavior
- Given the typical manufacturing process, is representative of that characteristic during operation when you meet the typical-value conditions or other specified conditions

Typical values are provided as design guidelines and are neither tested nor guaranteed.

3.8.1 Example 1

This is an example of an operating behavior that includes a typical value:

Symbol	Description	Min.	Тур.	Max.	Unit
I _{WP}	Digital I/O weak pullup/pulldown current	10	70	130	μΑ

3.8.2 Example 2

This is an example of a chart that shows typical values for various voltage and temperature conditions:



4.2 Moisture handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
MSL	Moisture sensitivity level	—	3	—	1

1. Determined according to IPC/JEDEC Standard J-STD-020, *Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices*.

4.3 ESD handling ratings

Symbol	Description	Min.	Max.	Unit	Notes
V _{HBM}	Electrostatic discharge voltage, human body model	-2000	+2000	V	1
V _{CDM}	Electrostatic discharge voltage, charged-device model	-500	+500	V	2
I _{LAT}	Latch-up current at ambient temperature of 105°C	-100	+100	mA	3

- 1. Determined according to JEDEC Standard JESD22-A114, *Electrostatic Discharge (ESD) Sensitivity Testing Human Body Model (HBM)*.
- 2. Determined according to JEDEC Standard JESD22-C101, Field-Induced Charged-Device Model Test Method for Electrostatic-Discharge-Withstand Thresholds of Microelectronic Components.
- 3. Determined according to JEDEC Standard JESD78, IC Latch-Up Test.

4.4 Voltage and current operating ratings

Symbol	Description	Min.	Max.	Unit
V _{DD}	Digital supply voltage	-0.3	3.8	V
I _{DD}	Digital supply current	—	155	mA
V _{DIO}	Digital input voltage (except RESET, EXTAL, and XTAL)	-0.3		V
V _{AIO}	Analog ¹ , RESET, EXTAL, and XTAL input voltage	-0.3	V _{DD} + 0.3	V
I _D	Maximum current single pin limit (applies to all digital pins)	-25	25	mA
V _{DDA}	Analog supply voltage	V _{DD} – 0.3	V _{DD} + 0.3	V
VREGIN	USB regulator input	-0.3	6.0	V
V _{BAT}	RTC battery supply voltage	-0.3	3.8	V

1. Analog pins are defined as pins that do not have an associated general purpose I/O port function.

5 General



5.1 AC electrical characteristics

Unless otherwise specified, propagation delays are measured from the 50% to the 50% point, and rise and fall times are measured at the 20% and 80% points, as shown in the following figure.



The midpoint is V_{IL} + $(V_{IH} - V_{IL})/2$.

Figure 1. Input signal measurement reference

5.2 Nonswitching electrical specifications

5.2.1 Voltage and current operating requirements

Table 1. Voltage and current operating requirements

Symbol	Description	Min.	Max.	Unit	Notes
V _{DD}	Supply voltage	1.71	3.6	V	
V _{DDA}	Analog supply voltage	1.71	3.6	V	
$V_{DD} - V_{DDA}$	V _{DD} -to-V _{DDA} differential voltage	-0.1	0.1	V	
$V_{SS} - V_{SSA}$	V _{SS} -to-V _{SSA} differential voltage	-0.1	0.1	V	
V _{BAT}	RTC battery supply voltage	1.71	3.6	V	
V _{IH}	Input high voltage				
	• $2.7 \text{ V} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}$	$0.7 \times V_{DD}$	_	V	
	• $1.7 \text{ V} \le \text{V}_{\text{DD}} \le 2.7 \text{ V}$	$0.75 \times V_{DD}$	_	V	
V _{IL}	Input low voltage				
	• $2.7 \text{ V} \le \text{V}_{\text{DD}} \le 3.6 \text{ V}$	_	$0.35 \times V_{DD}$	V	
	• $1.7 \text{ V} \le \text{V}_{\text{DD}} \le 2.7 \text{ V}$	—	$0.3 \times V_{DD}$	V	
V _{HYS}	Input hysteresis	$0.06 \times V_{DD}$	—	V	
I _{ICIO}	I/O pin DC injection current — single pin				1
	 V_{IN} < V_{SS}-0.3V (Negative current injection) 			mA	
	 V_{IN} > V_{DD}+0.3V (Positive current injection) 	-3	—		
		—	+3		

Table continues on the next page ...



Symbol	Description	Min.	Тур.	Max.	Unit	Notes
I _{DD_RUN}	Run mode current — all peripheral clocks enabled, code executing from flash					3, 4
	• @ 1.8 V	_	17.04	19.3	mΔ	
	• @ 3.0 V		17.04	10.0	11// (
	• @ 25°C	_	17.01	18.9	mA	
	• @ 125°C	_	19.8	21.3	mA	
I _{DD_WAIT}	Wait mode high frequency current at 3.0 V — all peripheral clocks disabled	_	7.95	9.5	mA	2
I _{DD_WAIT}	Wait mode reduced frequency current at 3.0 V — all peripheral clocks disabled		5.88	7.4	mA	5
I _{DD_STOP}	Stop mode current at 3.0 V	_	320	436	μA	
	• @ -40 to 25°C • @ 50°C		360	489		
	• @ 70°C		410	620		
	• @ 105°C		610	1100		
I _{DD_VLPR}	Very-low-power run mode current at 3.0 V — all peripheral clocks disabled	_	754		μΑ	6
I _{DD_VLPR}	Very-low-power run mode current at 3.0 V — all peripheral clocks enabled		1.1		mA	7
I _{DD_VLPW}	Very-low-power wait mode current at 3.0 V		437	—	μA	8
I _{DD_VLPS}	Very-low-power stop mode current at 3.0 V	_	7.33	24.2	μΑ	
	• @ -40 to 25°C • @ 50°C		14	32		
	• @ 70°C		28	48		
			110	280		
I _{DD_LLS}	Low leakage stop mode current at 3.0 V • @ -40 to 25°C	_	3.14	4.8	μΑ	
	• @ 50°C		6.48	28.3		
	• @ 70°C • @ 105°C		13.85	44.6		
			55.53	71.3		
I _{DD_VLLS3}	Very low-leakage stop mode 3 current at 3.0 V	—	2.19	3.4	μΑ	
	• @ -40 to 25°C		4.35	4.35		
	• @ 70°C		8.92	24.6		
	• @ 105°C		35.33	45.3		
I _{DD_VLLS2}	Very low-leakage stop mode 2 current at 3.0 V	_	1.77	3.1	μA	
	• @ -40 to 25°C • @ 50°C		2.81	13.8		
	• @ 70°C		5.20	22.3		
	- @ 105 0		19.88	34.2		

Table 6. Power consumption operating behaviors (continued)

Table continues on the next page...



General



Figure 3. VLPR mode supply current vs. core frequency

5.2.6 EMC radiated emissions operating behaviors Table 7. EMC radiated emissions operating behaviors 1

Symbol	Description	Frequency band (MHz)	Тур.	Unit	Notes
V _{RE1}	Radiated emissions voltage, band 1	0.15–50	19	dBµV	2, 3
V _{RE2}	Radiated emissions voltage, band 2	50–150	21	dBµV	
V _{RE3}	Radiated emissions voltage, band 3	150–500	19	dBµV	
V _{RE4}	Radiated emissions voltage, band 4	500–1000	11	dBµV	
V _{RE_IEC}	IEC level	0.15–1000	L	_	3, 4

1. This data was collected on a MK20DN128VLH5 64pin LQFP device.

2. Determined according to IEC Standard 61967-1, Integrated Circuits - Measurement of Electromagnetic Emissions, 150 kHz to 1 GHz Part 1: General Conditions and Definitions and IEC Standard 61967-2, Integrated Circuits - Measurement of Electromagnetic Emissions, 150 kHz to 1 GHz Part 2: Measurement of Radiated Emissions – TEM Cell and Wideband TEM Cell Method. Measurements were made while the microcontroller was running basic application code. The reported emission level is the value of the maximum measured emission, rounded up to the next whole number, from among the measured orientations in each frequency range.

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- 3. $V_{DD} = 3.3 \text{ V}$, $T_A = 25 \text{ °C}$, $f_{OSC} = 12 \text{ MHz}$ (crystal), $f_{SYS} = 48 \text{ MHz}$, $f_{BUS} = 48 \text{ MHz}$
- 4. Specified according to Annex D of IEC Standard 61967-2, Measurement of Radiated Emissions TEM Cell and Wideband TEM Cell Method

5.2.7 Designing with radiated emissions in mind

To find application notes that provide guidance on designing your system to minimize interference from radiated emissions:

- 1. Go to www.freescale.com.
- 2. Perform a keyword search for "EMC design."

5.2.8 Capacitance attributes

Table 8. Capacitance attributes

Symbol	Description	Min.	Max.	Unit
C _{IN_A}	Input capacitance: analog pins	—	7	pF
C _{IN_D}	Input capacitance: digital pins	_	7	pF

5.3 Switching specifications

5.3.1 Device clock specifications

Table 9. Device clock specifications

Symbol	Description	Min.	Max.	Unit	Notes
	Normal run mode	9			
f _{SYS}	System and core clock	_	50	MHz	
f _{BUS}	Bus clock	—	50	MHz	
f _{FLASH}	Flash clock	_	25	MHz	
f _{LPTMR}	LPTMR clock	—	25	MHz	
	VLPR mode ¹				
f _{SYS}	System and core clock	_	4	MHz	
f _{BUS}	Bus clock	—	4	MHz	
f _{FLASH}	Flash clock	—	1	MHz	
f _{ERCLK}	External reference clock	_	16	MHz	
f _{LPTMR_pin}	LPTMR clock	—	25	MHz	
f _{LPTMR_ERCLK}	LPTMR external reference clock	—	16	MHz	
f _{I2S_MCLK}	I2S master clock	_	12.5	MHz	
f _{I2S_BCLK}	I2S bit clock		4	MHz	

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Figure 8. EzPort Timing Diagram

6.5 Security and integrity modules

6.5.1 Drylce Tamper Electrical Specifications

Information about security-related modules is not included in this document and is available only after a nondisclosure agreement (NDA) has been signed. To request an NDA, please contact your local Freescale sales representative.

6.6 Analog

6.6.1 ADC electrical specifications

The 16-bit accuracy specifications listed in Table 24 and Table 25 are achievable on the differential pins ADCx_DP0, ADCx_DM0.

All other ADC channels meet the 13-bit differential/12-bit single-ended accuracy specifications.



6.6.1.1 16-bit ADC operating conditions Table 24. 16-bit ADC operating conditions

Symbol	Description	Conditions	Min.	Typ. ¹	Max.	Unit	Notes
V _{DDA}	Supply voltage	Absolute	1.71	—	3.6	V	
ΔV_{DDA}	Supply voltage	Delta to V _{DD} (V _{DD} – V _{DDA})	-100	0	+100	mV	2
ΔV_{SSA}	Ground voltage	Delta to V_{SS} ($V_{SS} - V_{SSA}$)	-100	0	+100	mV	2
V _{REFH}	ADC reference voltage high		1.13	V _{DDA}	V _{DDA}	V	
V _{REFL}	ADC reference voltage low		V _{SSA}	V _{SSA}	V _{SSA}	V	
V _{ADIN}	Input voltage	16-bit differential mode	VREFL	_	31/32 * VREFH	V	
		All other modes	VREFL	—	VREFH		
C _{ADIN}	Input capacitance	16-bit mode	_	8	10	pF	
		 8-bit / 10-bit / 12-bit modes 	_	4	5		
R _{ADIN}	Input resistance		_	2	5	kΩ	
R _{AS}	Analog source resistance	13-bit / 12-bit modes f _{ADCK} < 4 MHz	_	_	5	kΩ	3
f _{ADCK}	ADC conversion clock frequency	≤ 13-bit mode	1.0		18.0	MHz	4
f _{ADCK}	ADC conversion clock frequency	16-bit mode	2.0	_	12.0	MHz	4
C _{rate}	ADC conversion	≤ 13-bit modes					5
	rate	No ADC hardware averaging	20.000	_	818.330	Ksps	
		Continuous conversions enabled, subsequent conversion time					
C _{rate}	ADC conversion	16-bit mode					5
		No ADC hardware averaging Continuous conversions enabled, subsequent conversion time	37.037		461.467	Ksps	

1. Typical values assume V_{DDA} = 3.0 V, Temp = 25 °C, f_{ADCK} = 1.0 MHz, unless otherwise stated. Typical values are for reference only, and are not tested in production.

- 2. DC potential difference.
- 3. This resistance is external to MCU. To achieve the best results, the analog source resistance must be kept as low as possible. The results in this data sheet were derived from a system that had < 8 Ω analog source resistance. The R_{AS}/C_{AS} time constant should be kept to < 1 ns.
- 4. To use the maximum ADC conversion clock frequency, CFG2[ADHSC] must be set and CFG1[ADLPC] must be clear.
- 5. For guidelines and examples of conversion rate calculation, download the ADC calculator tool.



Symbol	Description	Conditions ¹ .	Min.	Typ. ²	Max.	Unit	Notes
EQ	Quantization	16-bit modes	—	-1 to 0	_	LSB ⁴	
	error	 ≤13-bit modes 	—	—	±0.5		
ENOB	Effective number	16-bit differential mode					6
	of bits	• Avg = 32	12.8	14.5	—	bits	
		• Avg = 4	11.9	13.8	_	bits	
		16-bit single-ended mode					
		• Avg = 32	12.2	13.9	_	bits	
		• Avg = 4	11.4	13.1	_	bits	
SINAD	Signal-to-noise plus distortion	See ENOB	6.02	2 × ENOB + 1	1.76	dB	
THD	Total harmonic distortion	16-bit differential modeAvg = 32	_	-94	_	dB	7
		16-bit single-ended modeAvg = 32	_	-85	_	dB	
SFDR	Spurious free dynamic range	16-bit differential modeAvg = 32	82	95	_	dB	7
		16-bit single-ended modeAvg = 32	78	90	_	dB	
E _{IL}	Input leakage error			$I_{In} \times R_{AS}$		mV	I _{In} = leakage current
							(refer to the MCU's voltage and current operating ratings)
	Temp sensor slope	Across the full temperature range of the device	1.55	1.62	1.69	mV/°C	8
V _{TEMP25}	Temp sensor voltage	25 °C	706	716	726	mV	8

Table 25. 16-bit ADC characteristics ($V_{REFH} = V_{DDA}$, $V_{REFL} = V_{SSA}$) (continued)

- 1. All accuracy numbers assume the ADC is calibrated with $V_{REFH} = V_{DDA}$
- Typical values assume V_{DDA} = 3.0 V, Temp = 25 °C, f_{ADCK} = 2.0 MHz unless otherwise stated. Typical values are for reference only and are not tested in production.
- The ADC supply current depends on the ADC conversion clock speed, conversion rate and ADC_CFG1[ADLPC] (low power). For lowest power operation, ADC_CFG1[ADLPC] must be set, the ADC_CFG2[ADHSC] bit must be clear with 1 MHz ADC conversion clock speed.
- 4. 1 LSB = $(V_{REFH} V_{REFL})/2^N$
- 5. ADC conversion clock < 16 MHz, Max hardware averaging (AVGE = %1, AVGS = %11)
- 6. Input data is 100 Hz sine wave. ADC conversion clock < 12 MHz.
- 7. Input data is 1 kHz sine wave. ADC conversion clock < 12 MHz.

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NP

rempheral operating requirements and behaviors



Figure 12. Typical hysteresis vs. Vin level (VDD = 3.3 V, PMODE = 0)







6.8.3 I²C switching specifications

See General switching specifications.

6.8.4 UART switching specifications

See General switching specifications.

6.8.5 Normal Run, Wait and Stop mode performance over the full operating voltage range

This section provides the operating performance over the full operating voltage for the device in Normal Run, Wait and Stop modes.

Num.	Characteristic	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
S1	I2S_MCLK cycle time	40	—	ns
S2	I2S_MCLK (as an input) pulse width high/low	45%	55%	MCLK period
S3	I2S_TX_BCLK/I2S_RX_BCLK cycle time (output)	80	—	ns
S4	I2S_TX_BCLK/I2S_RX_BCLK pulse width high/low	45%	55%	BCLK period
S5	I2S_TX_BCLK/I2S_RX_BCLK to I2S_TX_FS/ I2S_RX_FS output valid	_	15	ns
S6	I2S_TX_BCLK/I2S_RX_BCLK to I2S_TX_FS/ I2S_RX_FS output invalid	0	—	ns
S7	I2S_TX_BCLK to I2S_TXD valid	—	15	ns

Table 37. I2S/SAI master mode timing

Table continues on the next page...



Peripheral operating requirements and behaviors



Figure 21. I2S/SAI timing — slave modes

6.8.6 VLPR, VLPW, and VLPS mode performance over the full operating voltage range

This section provides the operating performance over the full operating voltage for the device in VLPR, VLPW, and VLPS modes.

Table 39. I2S/SAI master mode timing in VLPR, VLPW, and VLPS modes(full voltage range)

Num.	Characteristic	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
S1	I2S_MCLK cycle time	62.5	—	ns
S2	I2S_MCLK pulse width high/low	45%	55%	MCLK period
S3	I2S_TX_BCLK/I2S_RX_BCLK cycle time (output)	250	—	ns
S4	I2S_TX_BCLK/I2S_RX_BCLK pulse width high/low	45%	55%	BCLK period
S5	I2S_TX_BCLK/I2S_RX_BCLK to I2S_TX_FS/ I2S_RX_FS output valid	_	45	ns
S6	I2S_TX_BCLK/I2S_RX_BCLK to I2S_TX_FS/ I2S_RX_FS output invalid	0	-	ns
S7	I2S_TX_BCLK to I2S_TXD valid	—	45	ns
S8	I2S_TX_BCLK to I2S_TXD invalid	0	—	ns
S9	I2S_RXD/I2S_RX_FS input setup before I2S_RX_BCLK	75	_	ns
S10	I2S_RXD/I2S_RX_FS input hold after I2S_RX_BCLK	0	—	ns



rempheral operating requirements and behaviors



Figure 22. I2S/SAI timing — master modes

Table 40. I2S/SAI slave mode timing in VLPR, VLPW, and VLPS modes (full voltage range)

Num.	Characteristic	Min.	Max.	Unit
	Operating voltage	1.71	3.6	V
S11	I2S_TX_BCLK/I2S_RX_BCLK cycle time (input)	250	—	ns
S12	I2S_TX_BCLK/I2S_RX_BCLK pulse width high/low (input)	45%	55%	MCLK period
S13	I2S_TX_FS/I2S_RX_FS input setup before I2S_TX_BCLK/I2S_RX_BCLK	30	_	ns
S14	I2S_TX_FS/I2S_RX_FS input hold after I2S_TX_BCLK/I2S_RX_BCLK		-	ns
S15	I2S_TX_BCLK to I2S_TXD/I2S_TX_FS output valid	_	87	ns
S16	I2S_TX_BCLK to I2S_TXD/I2S_TX_FS output invalid	0	—	ns
S17	I2S_RXD setup before I2S_RX_BCLK	30	—	ns
S18	I2S_RXD hold after I2S_RX_BCLK	2	—	ns
S19	I2S_TX_FS input assertion to I2S_TXD output valid ¹	_	72	ns

1. Applies to first bit in each frame and only if the TCR4[FSE] bit is clear



NOTE

- The analog input signals ADC0_SE10, ADC0_SE11, ADC0_DP1, and ADC0_DM1 are available only for K11, K12, K21, and K22 devices and are not present on K10 and K20 devices.
- The TRACE signals on PTE0, PTE1, PTE2, PTE3, and PTE4 are available only for K11, K12, K21, and K22 devices and are not present on K10 and K20 devices.
- If the VBAT pin is not used, the VBAT pin should be left floating. Do not connect VBAT pin to VSS.
- The FTM_CLKIN signals on PTB16 and PTB17 are available only for K11, K12, K21, and K22 devices and is not present on K10 and K20 devices. For K22D devices this signal is on ALT4, and for K22F devices, this signal is on ALT7.
- The FTM0_CH2 signal on PTC5/LLWU_P9 is available only for K11, K12, K21, and K22 devices and is not present on K10 and K20 devices.
- The I2C0_SCL signal on PTD2/LLWU_P13 and I2C0_SDA signal on PTD3 are available only for K11, K12, K21, and K22 devices and are not present on K10 and K20 devices.

121	Default	ALT0	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
MAP Bga										
E4	ADC0_SE10	ADC0_SE10	PTE0	SPI1_PCS1	UART1_TX		TRACE_CLKOUT	I2C1_SDA	RTC_CLKOUT	
E3	ADC0_SE11	ADC0_SE11	PTE1/ LLWU_P0	SPI1_SOUT	UART1_RX		TRACE_D3	I2C1_SCL	SPI1_SIN	
E2	ADC0_DP1	ADC0_DP1	PTE2/ LLWU_P1	SPI1_SCK	UART1_CTS_b		TRACE_D2			
F4	ADC0_DM1	ADC0_DM1	PTE3	SPI1_SIN	UART1_RTS_b		TRACE_D1		SPI1_SOUT	
H7	DISABLED		PTE4/ LLWU_P2	SPI1_PCS0	UART3_TX		TRACE_D0			
G4	DISABLED		PTE5	SPI1_PCS2	UART3_RX					
E6	VDD	VDD								
G7	VSS	VSS								
K3	ADC0_SE4a	ADC0_SE4a	PTE16	SPI0_PCS0	UART2_TX	FTM_CLKIN0		FTM0_FLT3		
H4	ADC0_SE5a	ADC0_SE5a	PTE17	SPI0_SCK	UART2_RX	FTM_CLKIN1		LPTMR0_ALT3		
A11	ADC0_SE6a	ADC0_SE6a	PTE18	SPI0_SOUT	UART2_CTS_b	I2C0_SDA				
A10	ADC0_SE7a	ADC0_SE7a	PTE19	SPI0_SIN	UART2_RTS_b	I2C0_SCL				
L6	VSS	VSS								
K1	ADC0_DP0	ADC0_DP0								
K2	ADC0_DM0	ADC0_DM0								



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121 Map	Default	ALTO	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
BGA										
J11	RESET_b	RESET_b		1000.001						
G11	ADC0_SE8	ADC0_SE8	PTB0/ LLWU_P5	12C0_SCL	FIM1_CH0			FIM1_QD_PHA		
G10	ADC0_SE9	ADC0_SE9	PTB1	I2C0_SDA	FTM1_CH1			FTM1_QD_PHB		
G9	ADC0_SE12	ADC0_SE12	PTB2	I2C0_SCL	UART0_RTS_b			FTM0_FLT3		
G8	ADC0_SE13	ADC0_SE13	PTB3	I2C0_SDA	UART0_CTS_b/ UART0_COL_b			FTM0_FLT0		
D10	DISABLED		PTB10	SPI1_PCS0	UART3_RX			FTM0_FLT1		
C10	DISABLED		PTB11	SPI1_SCK	UART3_TX			FTM0_FLT2		
B11	DISABLED		PTB12	UART3_RTS_b	FTM1_CH0	FTM0_CH4		FTM1_QD_PHA		
C11	DISABLED		PTB13	UART3_CTS_b	FTM1_CH1	FTM0_CH5		FTM1_QD_PHB		
B10	DISABLED		PTB16	SPI1_SOUT	UART0_RX			EWM_IN	FTM_CLKIN0	
E9	DISABLED		PTB17	SPI1_SIN	UART0_TX			EWM_OUT_b	FTM_CLKIN1	
D9	DISABLED		PTB18		FTM2_CH0	I2S0_TX_BCLK				
C9	DISABLED		PTB19		FTM2_CH1	I2S0_TX_FS				
B9	ADC0_SE14	ADC0_SE14	PTC0	SPI0_PCS4	PDB0_EXTRG			I2S0_TXD1		
D8	ADC0_SE15	ADC0_SE15	PTC1/ LLWU_P6	SPI0_PCS3	UART1_RTS_b	FTM0_CH0		I2S0_TXD0		
C8	ADC0_SE4b/ CMP1_IN0	ADC0_SE4b/ CMP1_IN0	PTC2	SPI0_PCS2	UART1_CTS_b	FTM0_CH1		I2S0_TX_FS		
B8	CMP1_IN1	CMP1_IN1	PTC3/ LLWU_P7	SPI0_PCS1	UART1_RX	FTM0_CH2	CLKOUT	I2S0_TX_BCLK		
G3	VSS	VSS								
E5	VDD	VDD								
A8	DISABLED		PTC4/ LLWU_P8	SPI0_PCS0	UART1_TX	FTM0_CH3		CMP1_OUT		
D7	DISABLED		PTC5/ LLWU_P9	SPI0_SCK	LPTMR0_ALT2	I2S0_RXD0		CMP0_OUT	FTM0_CH2	
C7	CMP0_IN0	CMP0_IN0	PTC6/ LLWU_P10	SPI0_SOUT	PDB0_EXTRG	I2S0_RX_BCLK		I2S0_MCLK		
B7	CMP0_IN1	CMP0_IN1	PTC7	SPI0_SIN		I2S0_RX_FS				
A7	CMP0_IN2	CMP0_IN2	PTC8			I2S0_MCLK				
D6	CMP0_IN3	CMP0_IN3	PTC9			I2S0_RX_BCLK		FTM2_FLT0		
C6	DISABLED		PTC10	I2C1_SCL		I2S0_RX_FS				
C5	DISABLED		PTC11/ LLWU_P11	I2C1_SDA		I2S0_RXD1				
B6	DISABLED		PTC12							
A6	DISABLED		PTC13							
D5	DISABLED		PTC16		UART3_RX					
C4	DISABLED		PTC17		UART3_TX					
D4	DISABLED		PTD0/ LLWU_P12	SPI0_PCS0	UART2_RTS_b					
D3	ADC0_SE5b	ADC0_SE5b	PTD1	SPI0_SCK	UART2_CTS_b					



121 Map Bga	Default	ALTO	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
C3	DISABLED		PTD2/ LLWU_P13	SPI0_SOUT	UART2_RX	I2C0_SCL				
B3	DISABLED		PTD3	SPI0_SIN	UART2_TX	I2C0_SDA				
A3	ADC0_SE21	ADC0_SE21	PTD4/ LLWU_P14	SPI0_PCS1	UART0_RTS_b	FTM0_CH4		EWM_IN		
A2	ADC0_SE6b	ADC0_SE6b	PTD5	SPI0_PCS2	UART0_CTS_b/ UART0_COL_b	FTM0_CH5		EWM_OUT_b		
B2	ADC0_SE7b	ADC0_SE7b	PTD6/ LLWU_P15	SPI0_PCS3	UART0_RX	FTM0_CH6		FTM0_FLT0		
A1	ADC0_SE22	ADC0_SE22	PTD7	CMT_IRO	UART0_TX	FTM0_CH7		FTM0_FLT1		
F3	NC	NC								
H1	NC	NC								
H2	NC	NC								
J1	NC	NC								
J2	NC	NC								
J3	NC	NC								
H3	NC	NC								
K4	NC	NC								
H6	NC	NC								
J9	NC	NC								
J4	NC	NC								
H11	NC	NC								
F11	NC	NC								
E11	NC	NC								
D11	NC	NC								
E10	NC	NC								
F10	NC	NC								
F9	NC	NC								
F8	NC	NC								
E8	NC	NC								
E7	NC	NC								
F7	NC	NC								
A5	NC	NC								
B5	NC	NC								
B4	NC	NC								
A4	NC	NC								
A9	NC	NC								
B1	NC	NC								
C2	NC	NC								
C1	NC	NC								
D2	NC	NC								
L		1	1		1	1	1	1		



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121 Map Bga	Default	ALTO	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	EzPort
D1	NC	NC								
E1	NC	NC								

8.2 K11 Pinouts

The below figure shows the pinout diagram for the devices supported by this document. Many signals may be multiplexed onto a single pin. To determine what signals can be used on which pin, see the previous section.

	1	2	3	4	5	6	7	8	9	10	11	
A	PTD7	PTD5	PTD4/ LLWU_P14	NC	NC	PTC13	PTC8	PTC4/ LLWU_P8	NC	PTE19	PTE18	А
в	NC	PTD6/ LLWU_P15	PTD3	NC	NC	PTC12	PTC7	PTC3/ LLWU_P7	PTC0	PTB16	PTB12	в
с	NC	NC	PTD2/ LLWU_P13	PTC17	PTC11/ LLWU_P11	PTC10	PTC6/ LLWU_P10	PTC2	PTB19	PTB11	PTB13	с
D	NC	NC	PTD1	PTD0/ LLWU_P12	PTC16	PTC9	PTC5/ LLWU_P9	PTC1/ LLWU_P6	PTB18	PTB10	NC	D
E	NC	PTE2/ LLWU_P1	PTE1/ LLWU_P0	PTE0	VDD	VDD	NC	NC	PTB17	NC	NC	E
F	NC	NC	NC	PTE3	VDDA	VSSA	NC	NC	NC	NC	NC	F
G	NC	NC	VSS	PTE5	VREFH	VREFL	VSS	PTB3	PTB2	PTB1	PTB0/ LLWU_P5	G
н	NC	NC	NC	PTE17	TAMPER1	NC	PTE4/ LLWU_P2	PTA1	PTA3	PTA17	NC	н
J	NC	NC	NC	NC	TAMPER2	PTA0	PTA2	PTA4/ LLWU_P3	NC	PTA16	RESET_b	J
к	ADC0_DP0	ADC0_DM0	PTE16	NC	DAC0_OUT/ CMP1_IN3/ ADC0_SE23	VBAT	PTA5	PTA12	PTA14	VSS	PTA19	к
L	ADC0_DP3	ADC0_DM3	VREF_OUT/ CMP1_IN5/ CMP0_IN5	XTAL32	EXTAL32	VSS	TAMPER0/ RTC_ WAKEUP_B	PTA13/ LLWU_P4	PTA15	VDD	PTA18	L
	1	2	3	4	5	6	7	8	9	10	11	1

